

December 2008

# **SuperFET™**

# **FCI11N60 600V N-Channel MOSFET**

#### **Features**

- 650V @T<sub>.I</sub> = 150°C
- Typ.  $R_{DS(on)} = 0.32\Omega$
- Ultra Low Gate Charge (typ. Q<sub>g</sub> = 40nC)
- Low Effective Output Capacitance (typ. Cosseff. = 95pF)
- 100% Avalanche Tested
- · RoHS Compliant

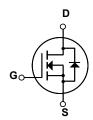


### **Description**

SuperFET<sup>TM</sup> is, Fairchild's proprietary, new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance.

This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. Consequently, SuperFET is very suitable for various AC/DC power conversion in switching mode operation for system miniaturization and higher efficiency.





## **Absolute Maximum Ratings**

Symbol	Parameter		FCI11N60	Unit	
V <sub>DSS</sub>	Drain-Source Voltage		600	V	
I <sub>D</sub>		tinuous ( $T_C = 25^{\circ}C$ ) tinuous ( $T_C = 100^{\circ}C$ )		11 7	A A
I <sub>DM</sub>	Drain Current - Puls	sed (	(Note 1)	33	Α
V <sub>GSS</sub>	Gate-Source voltage		± 30	V	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note:		(Note 2)	340	mJ
I <sub>AR</sub>	Avalanche Current	(	(Note 1)	11	А
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1		(Note 1)	12.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(	(Note 3)	4.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C) - Derate above 25°C		125 1.0	W W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
T <sub>L</sub>	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	°C	

### **Thermal Characteristics**

Symbol	Parameter	FCI11N60	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

# **Package Marking and Ordering Information**

<b>Device Marking</b>	Device	Package	Reel Size	Tape Width	Quantity
FCI11N60	FCI11N60	I <sup>2</sup> -PAK			50

# Electrical Characteristics T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	Conditions	Min	Тур	Max	Units
Off Charac	teristics			!	!	ļ.
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0V$ , $I_D = 250\mu A$ , $T_J = 25^{\circ}C$	600			V
		V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA, T <sub>J</sub> = 150°C		650		V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C		0.6		V/°C
BV <sub>DS</sub>	Drain-Source Avalanche Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 11A		700		V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 600V, V <sub>GS</sub> = 0V V <sub>DS</sub> = 480V, T <sub>C</sub> = 125°C			1 10	μ <b>Α</b> μ <b>Α</b>
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30V, V <sub>DS</sub> = 0V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30V, V <sub>DS</sub> = 0V	-		-100	nA
On Charac	teristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$	3.0		5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 5.5A		0.32	0.38	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40V, I <sub>D</sub> = 5.5A (Note 4)	-	9.7		S
Dynamic C	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 25V$ , $V_{GS} = 0V$ ,		1148	1490	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0MHz		671	870	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			63		pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 480V, V <sub>GS</sub> = 0V, f = 1.0MHz		35		pF
Coss eff.	Effective Output Capacitance	$V_{DS}$ = 0V to 400V, $V_{GS}$ = 0V	-	95		pF
Switching	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 300V, I <sub>D</sub> = 11A		34	80	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25\Omega$		98	205	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			119	250	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		56	120	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 480V, I <sub>D</sub> = 11A	-	40	52	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10V	-	7.2		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)	-	21		nC
Drain-Sour	rce Diode Characteristics and Maximur	n Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Dio	de Forward Current			11	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	orward Current	-		33	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 11A	-		1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>S</sub> = 11A	-	390		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$ (Note 4)		5.7		μС

#### Notes

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I $_{AS}$  = 5.5A, V $_{DD}$  = 50V, R $_{G}$  = 25 $\Omega$ , Starting T $_{J}$  = 25 $^{\circ}$ C
- 3. I\_{SD}  $\leq$  11A, di/dt  $\leq$  200A/µs, V\_{DD}  $\leq$  BV\_DSS, Starting T\_J = 25°C
- 4. Pulse Test: Pulse width  $\leq 300 \mu s, \ \text{Duty Cycle} \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

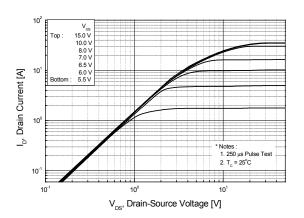
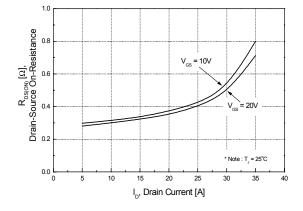


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage



**Figure 2. Transfer Characteristics** 

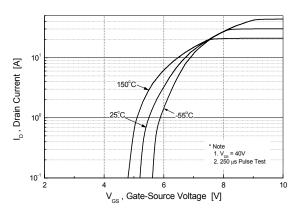


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

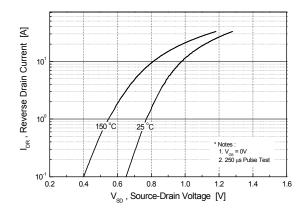


Figure 5. Capacitance Characteristics

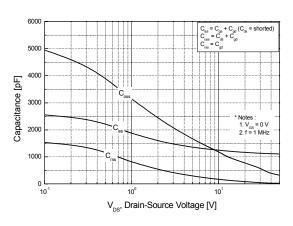
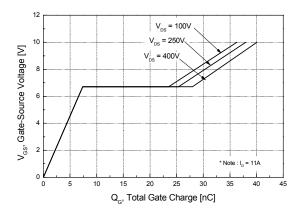


Figure 6. Gate Charge Characteristics



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# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

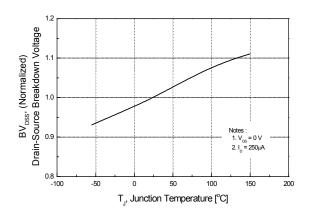


Figure 8. On-Resistance Variation vs. Temperature

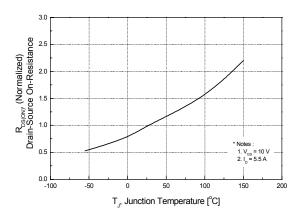


Figure 9. Maximum Safe Operating Area

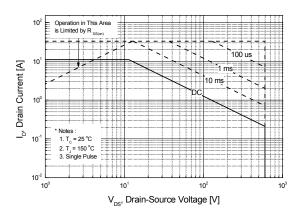


Figure 10. Maximum Drain Current vs. Case Temperature

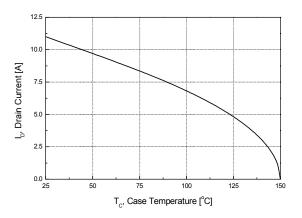
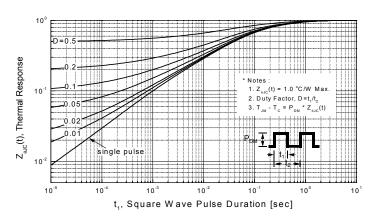
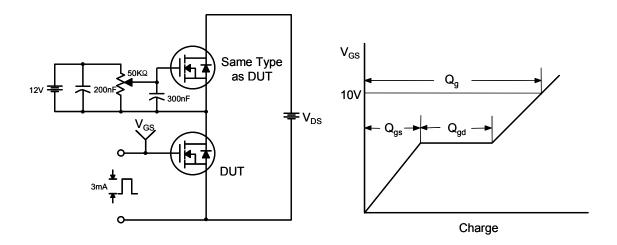


Figure 11. Transient Thermal Response Curve

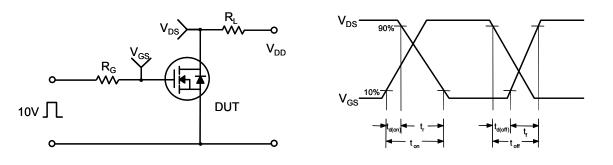


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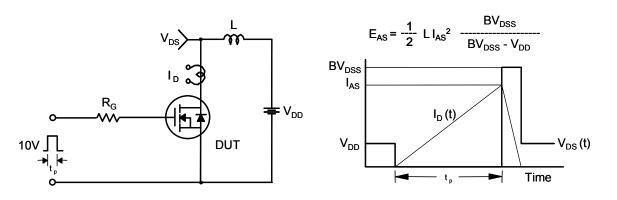
#### **Gate Charge Test Circuit & Waveform**



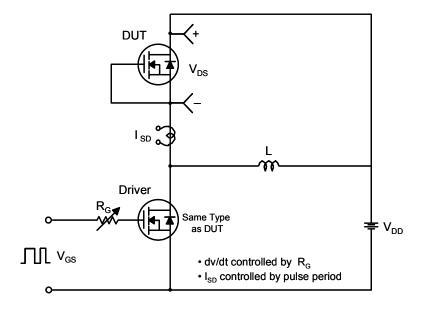
#### **Resistive Switching Test Circuit & Waveforms**

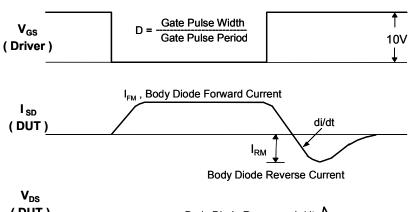


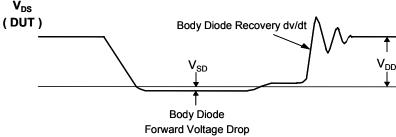
#### **Unclamped Inductive Switching Test Circuit & Waveforms**



#### Peak Diode Recovery dv/dt Test Circuit & Waveforms

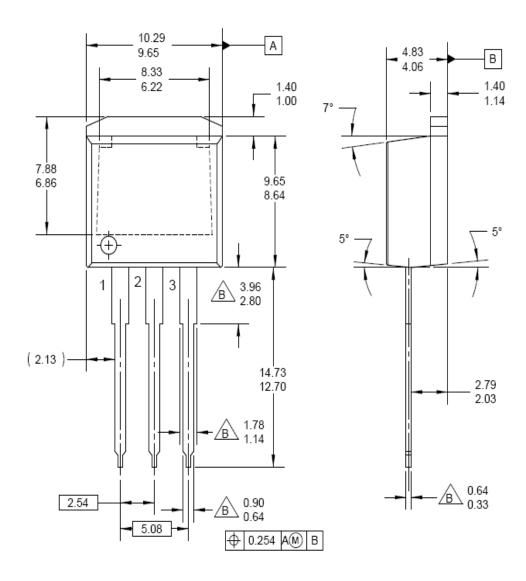






# **Mechanical Dimensions**

I<sup>2</sup> - PAK



Dimensions in Millimeters





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